AN6363, AN6363S

VTR Color AFC Circuit

Outline

The AN6363 and the AN6363S are integrated circuits designed for VTR color AFC and constitute a PAL-system color signal processing circuit for VTR by combining with the AN6360, the AN6360S, the AN6371 or the AN6371S.

Features

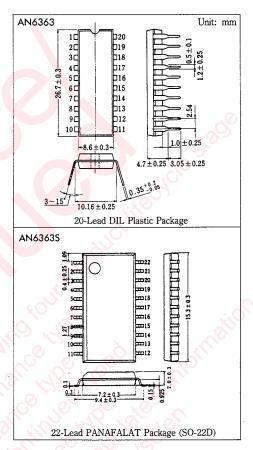
• The functions consist of:

AFC circuit

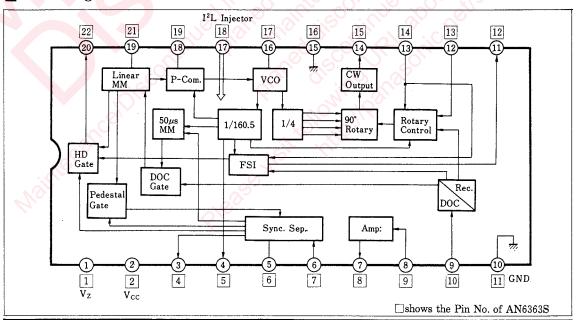
Synchro separation circuit

90° rotary circuit

Supply voltage either 9V or 12V



■ Block Diagram



Pin

() shows the Pin No. of AN6363S

Pin No.	Pin Name	Pin No.	Pin Name		
1 (1)	Zener Voltage	11 (12)	2nd FSI Output		
2 (2)	V _{cc}	12 (13)	ID Input		
3 (4)	Vcc Output for V Sync.	13 (14)	PG (Head SW) Input		
4 (5)	Sync Front Pulse Output	14 (15)	CW (627kHz) Output		
5 (6)	Low Pass Filter	15 (16)	GND		
6 (7)	Sync. Sep. Input	16 (17)	VCO Control		
7 (8)	White Clip Output	17 (18)	I ² L Injector		
8 (9)	Video Input	18 (19)	P-Com. Filter		
9 (10)	Rec./DOC Select	19 (21)	Linear Mono, Multi.		
10 (11)	GND	20 (22)	HD Output for Burst Gate		

In case of AN6363S, Pin No.3, @ are NC.

■ Absolute Maximum Ratings (Ta=25°C)

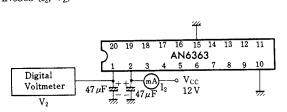
Item		Symbol	Rating	Unit	
Supply voltage		Vcc	13		
Power dissipatio	n AN6363	D	550		
(Ta=70°C)	AN6363S	P _D	270*	mW	
Operating ambient temperature		Topr	-20~+70	°C	
Storage temperature	AN6363	ar.	-40~+150		
	AN6363S	T _{stg}	-40~+125	d °C	

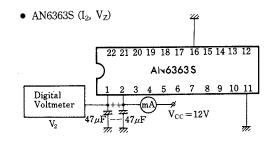
^{*}Indicates a package capability.

■ Electrical Characteristics (Vcc=V₂₋₁₅=1 2 V, Ta=25℃±2℃)

Item		Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Circuit current		I ₂	1		18		37	mA
Zener voltage		Vz	1		6.1		7.2	V
VCO Irequency control sensitivity	AN6363 AN6363S	$\frac{\beta_{14}}{\beta_{15}}$	3	I ₁₇ =28mA	270		490	kHz/V
HSS input sensitivity	AN6363 AN6363S	S ₈	4	I ₁₇ =28mA	0.5			V _{P-P}
VSS output amplitude	AN6363 AN6363S	v _{O3}	2	I ₁₇ =28mA	5		6.4	V
HD output amplitude	AN6363 AN6363S	v_{O20}	2	I ₁₇ =28mA	5		6.4	V
Sync. Front pulse output amplitude	AN6363 AN6363S	υ _{Ο4} υ _{Ο5}	2	I ₁₇ =28mA	5		6.4	V
Sync. Front pulse width	AN6363 AN6363S	t ₄	2	I ₁₇ =28mA		10.7		μs
627 kHz CW output amplitude	AN6363 AN6363S	$v_{ m O14} = v_{ m O15}$	2	I ₁₇ =28mA	1.3		2.3	V
627 kHz 2nd harmonic	AN6363 AN6363S	2f ₁₄ 2f ₁₅	5	l ₁₇ =28mA, Z _{i17} =6.8kΩ			-20	dB
PG input "H" voltage	AN6363 AN6363S	S ₁₃₋₁₁ S ₁₄₋₁₁	6	I ₁₇ =28mA, Z ₁₁₇ =6.8kΩ	4		7	v
PG input "L" voltage	AN6363 AN6363S	S _{13-L} S _{14-L}	6	I ₁₇ =28mA, Z _{i17} =6.8kΩ			0.8	v
2nd FSI output amplitude	AN6363 AN6363S	$\frac{v_{\mathrm{O11}}}{v_{\mathrm{O12}}}$	7	I ₁₇ =28mA	5		6.4	v
Rec./PB select sensitivity	AN6363 AN6363S	S ₉₋₁ S ₁₀₋₁	7	I ₁₇ =28mA	0.5			mA
DOC input sensitivity	AN6363 AN6363S	S ₉₋₂ S ₁₀₋₂	7	I ₁₇ =28mA			2	v
VCO oscillation frequency	AN6363 AN6363S	f _{OSC14} f _{OSC15}	8	I ₁₇ =28mA	2.3		4.1	MHz
ID input sensitivity	AN6363 AN6363S	S ₁₂ S ₁₃	9	I ₁₇ =28mA			0.2	v
Note) Operating supply vo	tage range	V _{CC(opt)} =8	.5~12.5	5V	<u> </u>			

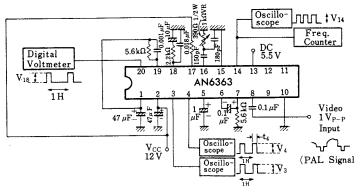






Test Circuit 2

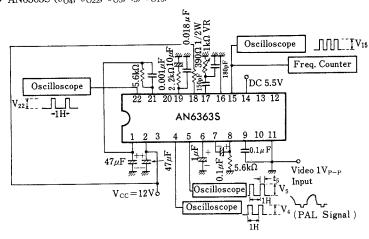
• AN6363 (v_{O3} , v_{O20} , v_{O4} , t_4 , v_{O14})



Variable resistor setting Note 1) Set to V_{18} a Pin $\ DC$ voltage when Pin $\$ input is OFF. Note 2) Adjust the $1k\Omega$ VR for the Pin $\$ so that a Pin $\$ voltage will be V_{18} when input is made to the Pin $\$. This setting becomes a basic condition

here after.

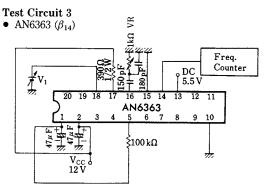
AN6363S (v_{O4}, v_{O22}, v_{O5}, t₅, v_{O15})



Variable resistor setting Note 1) Set to V₁₉ a Pin[®] DC voltage when Pin[®] input is OFF.

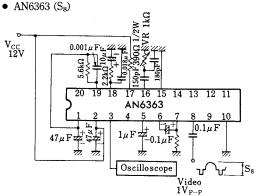
Note 2) Adjust the lkΩ VR for the Pin① so that a Pin② voltage will be V₁₀ when input is made to the Pin③.

This setting becomes a basic condition here after.



Note) Determine a four—fold Pin1 output frequency change as β_{14} when a V_{18} DC voltage is changed by $\pm 0.5 V$ without changing the Pin8 variable resistor set in Test Circuit 2. $\beta_{14} = 4 \times (f_{14(V18+0.5)} - f_{14(V18-0.5)})$

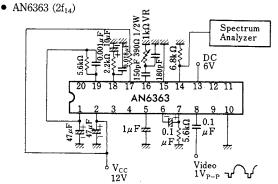
Test Circuit 4



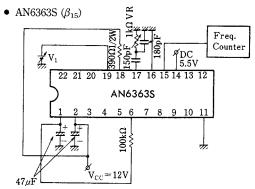
Note 1) Pin(\$ input signal amplitude when Pin(\$) output is normally made by increasing Pin(\$) input from 0

Note 2) Do not change the Pin® variable resistor. (same as Test Circuit 2)

Test Circuit 5

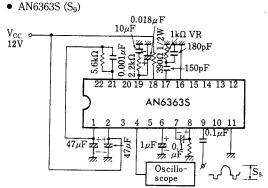


Note) Do not change the Pin® variable resistor. (same as Test Circuit 2)

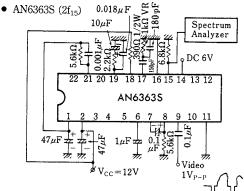


Note) Determine a four—fold Pin $\mathfrak D$ output frequency change as β_{15} when a V_{18} DC voltage is changed by $\pm 0.5 V$ without changing the Pin $\mathfrak D$ variable resistor set in Test Circuit 2.

 $\beta_{15} = 4 \times (f_{15(V19+0.5)} - f_{15(V19-0.5)})$



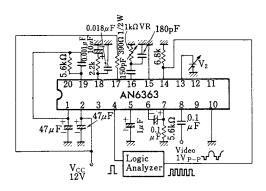
Note 1) Pin input signal amplitude when Pin output is normally made by increasing Pin input from 0 Note 2) Do not change the Pin variable resistor. (same as Test Circuit 2)



Note) Do not change the Pin variable resistor. (same as Test Circuit 2)

Test Circuit 6

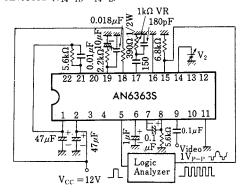
• AN6363 (S_{13-H}, S_{13-L})



Note 1) Pin DC voltages at which Pin output changes a phase by 90° at an intermediate timing of Pin output "H", and when it does not.

Note 2) Do not change the Pin variable resistor. (same as Test Circuit 2)

• AN6363S (S_{14-H}, S_{14-L})

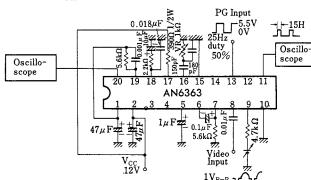


Note 1) Pin DC voltages at which Pin output changes a phase by 90° at an intermediate timing of Pin output "H", and when it does not.

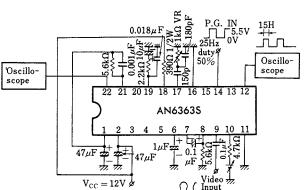
Note 2) Do not change the Pin variable resistor. (same as Test Circuit 2)

Test Circuit 7

• AN6363 $(v_{O11}, S_{9-1}, S_{9-2})$



• AN6363S (v_{O12} , S_{10-1} , S_{10-2})



Note) S_{9-1} : Pin9 inflow current which does not allow Pin1 output to be made as pulse output for about 15H after a rise fall of Pin3 PG input V_{11} : Pin1 output under the condition above S_{9-2} : Pin9 DC voltage at which Pin2 output is not made at all.

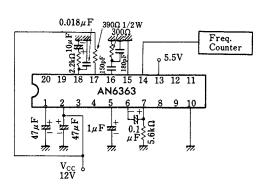
- · The PB mode is a Pin Open state.
- Do not change the Pin® variable resistor. (same as Test Circuit 2)

Note) S_{10-1} : Pin0 inflow current which does not allow Pin0 output to be made as pulse output for about 15H after a rise fall of Pin0 PG input V_{12} : Pin0 output under the condition above S_{10-2} : Pin0 DC voltage at which Pin0 output is not made at all.

- · The PB mode is a Pin@ Open state.
- · Do not change the $Pin\mathfrak{D}$ variable resistor. (same as Test Circuit 2)

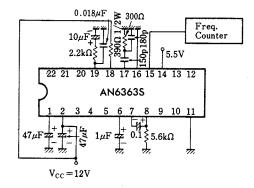
Test Circuit 8

AN6363 (f_{OSC14})



Note) Assume a four-fold Pin \mathbb{Q} output frequency as f_{14} . $f_{14} = 4 \times \text{(Pin}\mathbb{Q} \text{ output frequency)}$

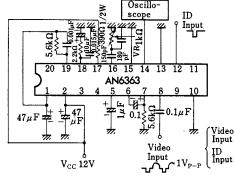
AN6363S (f_{OSC15})



Note) Assume a four-fold Pin output frequency as f_{15} . $f_{15}=4 \times (Pin \bigcirc output frequency)$

Test Circuit 9

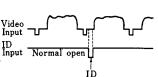
• AN6363 (S₁₂)



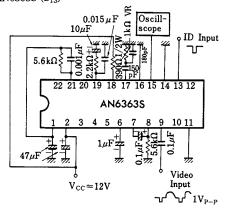
Note 1) ID input low—level voltage which causes another 90° phase change at an ID input timing as well, in addition to a 90° phase change of Pin 4 output before H. SYNC.

Note 2) Do not change the Pin® variable resistor. (same as Test Circuit 2)

Note 3) ID input is pules input which draws out a current from the Pin② at a burst timing.



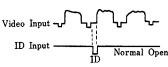
• AN6363S (S₁₃)



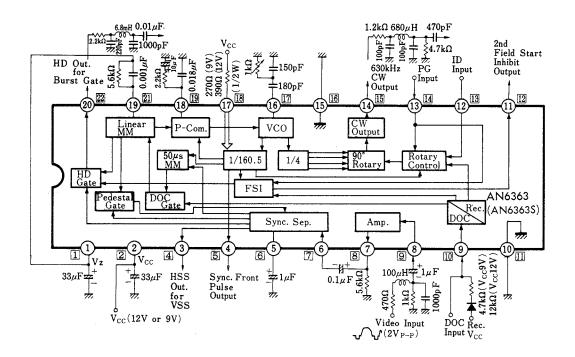
Note 1) ID input low—level voltage which causes another 90° phase change at an ID input timing as well, in addition to a 90° phase change of Pin® output before H. SYNC.

Note 2) Do not change the Pin0 variable resistor. (same as Test Circuit 2)

Note 3) ID input is pules input which draws out a current from the Pin(3) at a burst timing.



Application Circuit



□shows the Pin No. of AN6371S

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